

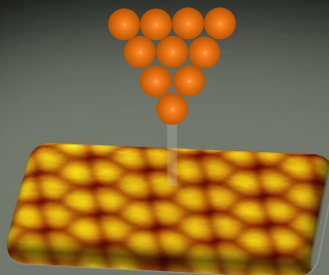
The International Symposium on Recent Trends in Analysis Techniques for Functional Materials and Devices

2nd -4th December 2015

Venue: Ginkgo-Hall, Osaka University

Sponsor: Osaka University and JSPS-NSFC

The international symposium has the highest topic about the surface potential measurement method of the scanning probe microscope and look back arguing from a wide point of view on application from the basics, the present conditions of this field. This symposium is given the understanding of nanoscience, nanotechnology. In this symposium, we invite the famous Professors to introduce their recent researches and also give the opportunity to present for the young researcher, PhD students of Osaka University. At the same time, we hope that this symposium can improve Osaka University to be connected for globalization of a study, the education environment.



Invited speaker

Prof. Ivan Stich (Slovak Academy of Sciences,
Bratislava, Slovakia)

Prof. Xucun Ma (Tsinghua University, China)

Prof. Zhihai Cheng (National Center for
Nanoscience and Technology, China)

Prof. Hidemi Shigekawa (University of Tsukuba)

Prof. Hideki Kawakatsu (University of Tokyo)

Prof. Yasuhiro Sugawara (Osaka University)

Prof. Yuji Kuwahara (Osaka University)

Prof. Tetsuya Yamamoto (Kochi University of Technology)

Associate Prof. Wilson Agerico Dino (Osaka University)

Prof. Jiping Ye (Nissan Arc)

Assistant Prof. Hikaru Nomura (Osaka University)

Dr. Justinas Palisaitis (Linkoping University Sweden)

Conference chairs

Yanjun Li (Osaka University)

Yasuhiro Sugawara (Osaka University)

Organizing Committee

Yasuhiro Sugawara (Osaka University)

Wilson Agerico Dino (Osaka University)

Xucun Ma (Tsinghua University, China)

Jun Liu (North University of China)

Program

Yoshitaka Naitoh (Osaka University)

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